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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/452,149	12/01/1999	YOKO IKEDA	501.37892X00	9942	
20457 7.	590 03/27/2003				
ANTONELLI TERRY STOUT AND KRAUS			EXAMINER		
	TH SEVENTEENTH STREET KIBLER, VIRGINIA N		RGINIA M		
ARLINGTON,	, VA 22209		ART UNIT	ART UNIT PAPER NUMBER	
			2623		
			DATE MAILED: 03/27/2003		

Please find below and/or attached an Office communication concerning this application or proceeding.

2							
	Application No.	Applicant(s)					
	09/452,149	IKEDA ET AL.					
Office Action Summary	Examiner	Art Unit					
	Virginia M Kibler	2623					
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the co	orrespondence address					
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status	i6(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days fill apply and will expire SIX (6) MONTHS from the application to become ABANDONEI	ely filed will be considered timely. he mailing date of this communicati (35 U.S.C. § 133).	on.				
1) Responsive to communication(s) filed on 13 J	<u>anuary 2003</u> .						
	is action is non-final.						
closed in accordance with the practice under	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims							
 4) ☐ Claim(s) 1-11 is/are pending in the application 4a) Of the above claim(s) is/are withdraw 							
	VII IIOIII COIISIGETAGOII.						
5) Claim(s) is/are allowed.							
	6) Claim(s) <u>1-11</u> is/are rejected.						
7) Claim(s) is/are objected to.							
8) Claim(s) are subject to restriction and/o Application Papers							
9) ☐ The specification is objected to by the Examiner.							
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.							
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
11) ☐ The proposed drawing correction filed on <u>13 January 2003</u> is: a) ☐ approved b) ☐ disapproved by the Examiner.							
If approved, corrected drawings are required in reply to this Office action. 12) The oath or declaration is objected to by the Examiner.							
,							
Priority under 35 U.S.C. §§ 119 and 120 13) Acknowledgment is made of a claim for foreign	nriority under 35 H S C & 110/a	\-(d) or (f)					
a) ⊠ All b) ☐ Some * c) ☐ None of:	i priority under 50 0.5.6. § 115(a)-(u) or (i).					
	s have been received						
_	 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 						
• • • • •	3. Copies of the certified copies of the priority documents have been received in this National Stage						
application from the International Bu * See the attached detailed Office action for a list	reau (PCT Rule 17.2(a)).						
14) Acknowledgment is made of a claim for domesti	c priority under 35 U.S.C. § 119(e) (to a provisional applica	ation).				
 a) The translation of the foreign language pro 15) Acknowledgment is made of a claim for domest 							
Attachment(s)	_						
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449) Paper No(s) 3 	5) Notice of Informal	y (PTO-413) Paper No(s) Patent Application (PTO-152)	_ ·				
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DETAILED ACTION

Response to Amendment

1. The amendment received on January 13, 2003 has been entered. Claims 1-11 remain pending. In light of the amendment, the previous objections to the drawings, abstract, and specification are withdrawn. The rejection of claims 1-3 under 35 U.S.C. 112, second paragraph is also withdrawn in light of the amendment.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1 and 2 are rejected under 35 U.S.C. 103(a) as being unpatentable over Aloni et al. (6,360,005) in view of Steffan et al. (5,999,003).

Regarding claim 1, Aloni et al. ("Aloni") discloses an inspecting system comprising an analyzing unit including a scanner (Figure 1, element 10) or an "image detection device." Aloni also discloses a diagnostic memory/processor or a "storage means" for storing detected images produced by the image detection device (Col. 15, lines 11-16). Aloni discloses providing a display (Figure 13, element 256) with a first area in which to display the images stored in the storage means (Col. 27, lines 5-9). Aloni further discloses allowing the user to classify the images into defect-classification areas (Col. 27, lines 10-17), thereby providing a means for moving to move an unclassified image to a classified area. Aloni does not expressly state



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displaying the second areas on the display with the first area. However, Steffan et al. ("Steffan") teaches that it is known to include a display means having a screen with a first area for displaying a plurality of the detected images (206, 208, 210, 212) and a plurality of bins (214, 216, 218, 220) or "second areas" for classifying the detected images. Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to have modified the display disclosed by Aloni to include displaying the classified images in a plurality of second areas, as taught by Steffan, in order to visualize the classification.

Regarding claim 2, the arguments analogous to those presented above for claim 1 are applicable to claim 2.

4. Claim 3 is rejected under 35 U.S.C. 103(a) as being unpatentable over Aloni et al. (6,360,005) in view of Steffan et al. (5,999,003) in further view of Nara et al. (6,421,122).

Regarding claim 3, the arguments analogous to those presented above for claim 1 are applicable to claim 3. Note Aloni discloses a defect detection system for inspecting electronic devices (Abstract, lines 1-3). Aloni further discloses providing information to the analyzing unit concerning images in the second areas of the screen (Col. 26, lines 44-58). Aloni et al. ("Aloni") does not recognize a method of manufacturing. However, Nara et al. ("Nara") teaches that an inspection apparatus can be applied to a manufacturing process or "method" of a semiconductor device (Col. 37, lines 53-57). Nara teaches a method of manufacturing an electronic device wherein use is made of a manufacturing apparatus for processing a workpiece to form an electronic device (Col. 42, lines 30-32). Nara also teaches controlling the production line using information obtained from said analyzing unit to process the workpiece (Col. 42, lines 48-54). Therefore, it would have been obvious to one of ordinary skill in the art at the time of



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the invention to have modified the inspection system disclosed by Aloni and Steffan to have included the method of manufacturing an electronic device, as taught by Nara, in order to prevent the generation of a large quantity of failure and raise productivity (Col. 37, lines 62-65).

5. Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over Aloni et al. (6,360,005) in view of Steffan et al. (5,999,003).

Regarding claim 4, Aloni et al. ("Aloni") discloses an inspecting system comprising an analyzing unit including a scanner (Figure 1, element 10) or an "image detection device" to produce images of semiconductor manufacturing defects (Abstract, lines 1 and 2). Aloni discloses providing a display (Figure 13, element 256) with a sorting display area in which to display the images with unclassified semiconductor manufacturing defects (Col. 27, lines 5-9). Aloni further discloses allowing the user to classify the images into defect-classification areas (Col. 27, lines 10-17), thereby providing a user-manipulated moving unit to move an unclassified image to a classified area. Aloni does not expressly state displaying the defect-classification areas on the display with the sorting display area. However, Steffan et al. ("Steffan") teaches that it is known to include a display means having a screen with a first area for displaying a plurality of the detected images (206, 208, 210, 212) and a plurality of bins (214, 216, 218, 220) or "second areas" for classifying the detected images. Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to have modified the display disclosed by Aloni to include displaying the classified images in a plurality of second areas, as taught by Steffan, in order to visualize the classification.



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Regarding claim 8, the arguments analogous to those presented above for claim 4 are applicable to claim 8. Note that Aloni discloses a method as well as a system (Title).

Regarding claim 7, Aloni discloses a memory to store predetermined information for the images including defect classification information (Col. 26, lines 59-67) and an adjuster unit to adjust the defect-classification information for the image to match the selected defect classification area (Col. 27, lines 1-20).

Regarding claim 11, the arguments analogous to those presented above for claim 7 are applicable to claim 11.

6. Claims 5, 6, 9, and 10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Aloni et al. (6,360,005) in view of Steffan et al. (5,999,003) as applied to claims 4 and 8 above, and further in view of Tanaka (5,995,087).

Regarding claim 5, Aloni and Steffan do not expressly state using a pointing device to drag and drop the image from the sorting display are into a defect-classification display area. However, this particular method user-manipulated movement is well known in the art. For example, Tanaka teaches that it is known to use a drag and drop operation as a user-manipulated moving unit (Col. 6, lines 33-39). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to have modified the user-manipulated moving unit disclosed by Aloni to expressly state a pointing device to point to, select, and drag-and-drop, as taught by Tanaka, as a design parameter.

Regarding claim 6, the arguments analogous to those presented above for claim 5 are applicable to claim 6. Note that Tanaka discloses using a mouse (Col. 6, lines 33-39).



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Regarding claims 9 and 10, the arguments analogous to those presented above for claims 5 and 6 are applicable to claims 9 and 10.

Contact Information

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Virginia M Kibler whose telephone number is (703) 306-4072. The examiner can normally be reached on Mon. - Thurs. 8:00 - 5:30 and every other Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amelia Au can be reached on (703) 308-6604. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 872-9314 for regular communications and (703) 872-9314 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 306-0377.

VK March 24, 2003

SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600